Software reliability using SPC: Gompertz

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Abstract—Software reliability models are very important for prediction and estimation of software reliability. In this paper the application of Gompertz Software Reliability Model with Statistical Process Control for software reliability is presented. Maximum Likelihood Estimation is used to estimate the parameters of the model. The model is applied on the cumulative quantities of Time domain software failure data collected from different sources.

Keywords-Statistical		Proce	ss	Control,	
Maximum Likelihood		Estimation, Goi		ompertz,	
Software	Reliability	Growth	Mode	l, Non	
Homogenous Poisson Process.					

I. INTRODUCTION

Over the past four decades, the deployment of computer system has grown more intensely. Software is everywhere, but we need reliable software. Software Reliability is defined as the probability of failure-free operation of a computer program in a specified environment for a specified time.

In general SRGMs are applicable to the late stages of testing in software development. They can provide very useful information about how to improve the reliability of software products. The problem with using SRGM to estimate failure content is that they have underlying assumptions that are often violated in practice, but empirical evidence has shown that many are quite robust despite these assumption violations. The problem is that, because of assumption violations, it is often difficult to know which models to apply in practice. Reliability quantities have usually been defined with respect to time, although it is possible to define them with respect to other variables. Most software reliability models are formulated in terms of random processes. It is traditional and important to use Non Homogenous Poisson Process (NHPP) to model the failure process. Models considered the probability of failure times or failures experienced and the nature of the variation of the random process with time. So, most models are time-based. Specification of a model generally includes specification of a function of time such as the mean value or failure intensity function.

Both static and dynamic software reliability models exist to assess the quality aspect of software. A static model uses software metrics, like complexity metrics, results of inspections, etc. to estimate the number of defects (or faults) in the software. A dynamic model uses the past failure discovery rate during software execution or cumulative failure profile over time to estimate the number of failures. It includes a time component, typically time between failures.

A failure is a departure from how software should behave during operation according to the requirements. Failures are dynamic: The software must be executing for a failure to occur. A fault is a defect in a program, that when executed causes failure(s). While a fault is a property of the program, a failure is a property of the program's execution.

Dynamic models measure and model the failure process itself. Because of this, they include a time component, which is typically based on recording times ti of successive failure i and i-1. Time may be recorded as execution time or calendar time. These models focus on the failure history of software. Failure history is influenced by a number of factors, including the environment within which the software is executed and how it is executed. A general assumption of these models is that software must be executed according to its operational profile; that is, test inputs are selected according to their probabilities of occurring during actual operation of the software in a given environment.

The expected value function for cumulative failures can be put into two shape classes: concave and Sshaped. S-shaped models are first convex, then concave. The S-shaped growth curves start at some fixed point and increase their growth rate monotonically to reach an inflection point. After this point, the growth rate approaches a final value asymptotically. The S-shaped models reflect an assumption that early testing is not as efficient as later testing, so there is a period during which the failuredetection rate increases. This period terminates, resulting in an inflection point in the S-shaped curve, when the failure-detection rate starts to decrease.

SPC concepts and methods are used to monitor the performance of a software process over time in order to verify that the process remains in the state of statistical control. The control chart is one of the seven tools for quality control. Software process control is used to secure the quality of the final product which will conform to predefined standards. In any process, regardless of how carefully it is maintained, a certain amount of natural variability will always exist. A process is said to be statistically "in-control" when it operates with only chance causes of variation. On the other hand, when assignable causes are present, then we say that the process is statistically "out-of-control."

Control charts should be capable to create an alarm when a shift in the level of one or more parameters of the underlying distribution or a nonrandom behavior occurs. Normally, such a situation will be reflected in the control chart by points plotted outside the control limits or by the presence of specific patterns. The most common non-random patterns are cycles, trends, mixtures and stratification (Koutras, 2007). For a process to be in control the control chart should not have any trend or nonrandom pattern.

II. NHPP MODELS

The NHPP group of models provides an analytical framework for describing the software failure phenomenon during testing. They are proved to be quite successful in practical software reliability engineering. They have been built upon various assumptions. If 't' is a continuous random variable with probability density function: $f(t, \theta_1, \theta_2, ..., \theta_k)$, and cumulative distribution function: F(t) where $\theta_1, \theta_2, ..., \theta_k$ are k unknown constant parameters. The mathematical relationship between the pdf and cdf is given as: f(t) = F'(t).

Let N(t) be the cumulative number of software failures by time "t. A non-negative integer-valued stochastic process N(t) is called a counting process, if N(t) represents the total number of occurrences of an event in the time interval [0, t] and satisfies these two properties:

If $t_1 < t_2$, then $N(t_1) \le N(t_2)$

If $t_1 < t_2$, then $N(t_2) - N(t_1)$ is the number of occurrences of the event in the interval $[t_1, t_2]$.

One of the most important counting processes is the Poisson process. A counting process, N(t), is said to be a Poisson process with intensity λ if

The initial condition is N(0) = 0.

The failure process, $N(t), \ has \ independent increments.$

The number of failures in any time interval of length s has a Poisson distribution with mean λs , that is,

$$P\left\{N\left(t+s\right)-N\left(t\right)=n\right\}=\frac{e^{-\lambda s}\left(\lambda s\right)^{n}}{n!}$$

Describing uncertainty about an infinite collection of random variables one for each value of 't' is called a stochastic counting process denoted by $\lceil N(t), t \ge 0 \rceil$.

The process $\{N(t), t \ge 0\}$ is assumed to follow a Poisson distribution with characteristic Mean Value Function m(t), representing the expected number of software failures by time 't'. Different models can be obtained by using different non decreasing m(t). The derivative of m(t) is called the failure intensity function $\lambda(t)$.

A Poisson process model for describing about the number of software failures in a given time (0, t) is given by the probability equation.

$$P[N(t) = y] = \frac{e^{-m(t)}[m(t)]^{y}}{y!}, \quad y = 0, 1, 2, \dots$$

Where, m(t) is a finite valued non negative and non decreasing function of 't' called the mean value function. Such a probability model for N(t) is said to be an NHPP model. The mean value function m(t) is the characteristic of the NHPP model.

The NHPP models are further classified into Finite and Infinite failure models. Let 'a' denote the expected number of faults that would be detected given infinite testing time in case of finite failure NHPP models. Then, the mean value function of the finite failure NHPP models can be written as: m(t) = aF(t). The failure intensity function $\lambda(t)$ is given by: $\lambda(t) = aF'(t)$.

III. GOMPERTZ SOFTWARE RELIABILITY MODEL

The simplest form of a software reliability growth model is an exponential one. However, S-shaped software reliability is more often observed than the exponential one. Some models use a nonhomogeneous Poisson process (NHPP) to model the failure process. The NHPP is characterized by its expected value function, m(t). This is the cumulative number of failures expected to occur after the software has executed for time t. Gompertz SRGM is based on an NHPP. In fact, many Japanese computer manufacturers and software houses have applied the Gompertz curve model, which is one of the simplest Sshaped software reliability growth models (Kececioglu, 1991). The Gompertz curve model gave good approximation to cumulative number of software faults observed (Satoh, 2000). It takes the number of faults per unit of time as independent Poisson random variables. The Gompertz model equation for software reliability is,

$$m(t) = ab^{c^t}$$

Where, 'a' is the upper limit approached the reliability, R at time t. 0<b<1, 0<c<1 are parameters to

be estimated form any one of the parameter estimation methods.

where

a is the expected total number of failures that would occur if testing was infinite.

b is the rate at which the failures detection rate decreases.

c models the growth pattern (small values model rapid early reliability growth, and large values model slow reliability growth).

The Gompertz distribution plays an important role in modeling survival times, human mortality and actuarial tables. According to the literature, the Gompertz distribution was formulated by Gompertz (1825) to fit mortality tables. Recently, many authors have contributed to the statistical methodology and characterization of this distribution. For example, Read (1983), Gordon (1990), Makany (1991), Franses (1994) and Wu & Lee (1999). Garg et al. (1970) studied the properties of the Gompertz distribution and obtained the maximum likelihood estimates for the parameters. There are several forms for the Gompertz distribution given in the literature. Some of these are given in Johnson et al. (1994). Gompertz software reliability model is a popular model to estimate remaining failures. It has been widely used to estimate software error content, it is a modified model of Moranda reliability model.

IV. MAXIMUM LIKELIHOOD ESTIMATION OF THE MODEL PARAMETERS

There are two methods of parameter determination. Parameter prediction and parameter estimation. Parameter prediction tries to establish the parameters of a model from the properties of the software product and the development process. Parameter estimation is used in subsystem or system test or operational phase where failure data are available. It is a statistical method trying to estimate model parameters based on failure times. A number of procedures can be used to estimate the parameters of Gompertz reliability model. Among these methods, The maximum likelihood estimation has been frequently considered to estimate the parameters of the Gompertz model.

The likelihood function of the sample is given by

$$L = e^{-m(t_n)} \prod_{i=1}^n \lambda(t_i)$$
$$L = e^{-ab^{c^{t_n}}} \prod_{i=1}^n \left[ab^{c^{t_i}} c^{t_i} \log b \log c \right]$$

It is usually easier to maximize the natural logarithm of the likelihood function rather than the

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likelihood function itself. So, the natural logarithm of the likelihood function can be written as:

$$\log L = \sum_{i=1}^{n} \left[\log a + \log \left(b^{c^{i_i}} \right) + \log \left(c^{i_i} \right) + \log \left(\log b \right) + \log \left(\log c \right) \right] - a b^{c^{i_n}}$$

The first derivatives of the natural logarithm of the total likelihood function in (2) with respect to a, b and c are given by:

$$\frac{\partial \log L}{\partial a} = \frac{n}{a} - ab^{c^{i_n}}$$

$$\frac{\partial \log L}{\partial b} = nc^{t_n} - \sum_{i=1}^n c^{t_i} - \frac{n}{\log b}$$

$$\frac{\partial \log L}{\partial c} = \frac{1}{c} \left(\frac{n}{\log c} + \sum_{i=1}^n t_i + \sum_{i=1}^n t_i c^{t_i} \log b \right) - n \log bt_n c^{t_n - 1}$$
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By equating equation (3) and (4) to zero, the maximum likelihood estimate of a and b can be given by the following estimation equation:

$$a = \frac{n}{b^{c^{\prime n}}} \qquad 6$$

$$b = e^{\frac{n}{nc^{\prime n} - \sum_{i=1}^{n} c^{\prime i}}} \qquad 7$$

Substituting 'b' in the equation (5), we get

$$\frac{\partial \log L}{\partial c} = \frac{1}{c} \left(\frac{n}{\log c} + \sum_{i=1}^{n} t_i + \sum_{i=1}^{n} t_i c^{t_i} \frac{n}{nc^{t_n} - \sum_{i=1}^{n} c^{t_i}} \right) - \frac{n^2}{nc^{t_n} - \sum_{i=1}^{n} c^{t_n}} - \frac{n^2}{nc^{t_n}} \frac{1}{nc^{t_n}} + \frac{1}{nc^{t_n}} \frac{1}{nc^{t_n}} \frac{1}{nc^{t_n}} + \frac{1}{nc$$

Obviously, it is very difficult to obtain a closed-form solution, iterative procedures must be used to solve these equations, numerically. The Newton-Raphson method is used to obtain the MLE of 'c'. Therefore, take the 2nd derivative with respect to 'c' and equating it to Zero.

$$\begin{split} \frac{\partial^2 \log L}{\partial c^2} &= \frac{1}{c} \Biggl(\sum_{i=1}^n t_i^2 c^{t_i-1} \frac{n}{nc^{t_s} - \sum_{i=1}^n c^{t_i}} + \sum_{i=1}^n t_i c^{t_i} \frac{-n}{\left(nc^{t_s} - \sum_{i=1}^n c^{t_i}\right)^2} \Biggl(nt_n c^{t_n-1} - \sum_{i=1}^n t_i c^{t_i-1} \Biggr) - \frac{n}{c\left(\log c\right)^2} \Biggr) \\ &\quad - \frac{1}{c^2} \Biggl(\sum_{i=1}^n t_i c^{t_i} \frac{n}{nc^{t_s} - \sum_{i=1}^n c^{t_i}} + \sum_{i=1}^n t_i + \frac{n}{\log c} \Biggr) \Biggr) \\ &\quad - n^2 t_n \frac{\left[\left(nc^{t_s} - \sum_{i=1}^n c^{t_i}\right) (t_n - 1) c^{t_s-2} - c^{t_s-1} \left(nt_n c^{t_s-1} - \sum_{i=1}^n t_i c^{t_i-1}\right) \right]}{\left(nc^{t_s} - \sum_{i=1}^n c^{t_i}\right)^2} \end{split}$$

Thus, once the value of c° is determined, an estimate of b° is easily obtained from (7). They are then substituted in equation (6) to get an estimate of a° .

V. TIME DOMAIN FAILURE DATA

The success of applying and using a software reliability model depends highly on the quality and accuracy of failure data collection which in turn depends on careful planning and organization. The data which is considered has been transformed so as to suit to the model under consideration.

The following tables shows the number of errors and the inter failure time.

TABLE I.	DATA SET #1:	DATA COLLECTED FROM (XIE, 200)2).
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Failu re Num ber	Cumul ative Time Betwee n Failure (h)	Failu re Num ber	Cumul ative Time Betwee n Failure (h)	Failu re Num ber	Cumul ative Time Betwee n Failure (h)
1	0.3002	11	1.1534	21	2.5681
2	0.3146	12	1.2157	22	2.7388
3	0.5393	13	1.2496	23	2.7787
4	0.5529	14	1.3407	24	4.5393
5	0.5872	15	1.3625	25	5.35
6	0.7192	16	1.5178	26	5.3727
7	0.7707	17	1.775	27	5.529
8	0.809	18	1.8029	28	6.7368
9	1.019	19	1.8221	29	7.0449
10	1.1487	20	1.8634	30	7.3868

TABLE II. DATA SET #2: ON-LINE DATA ENTRY IBM SOFTWARE PACKAGE

The data reported by Ohba (1984a) are recorded from testing an on-line data entry software package developed at IBM.

Failu re Num ber	Cumul ative Inter Failure Time	Failu re Num ber	Cumul ative Inter Failure Time	Failu re Num ber	Cumul ative Inter Failure Time
1	0.1	6	0.7	11	1.69
2	0.19	7	0.88	12	1.99
3	0.32	8	1.03	13	2.31
4	0.43	9	1.25	14	2.56
5	0.58	10	1.5	15	2.96

VI. RESULTS

The control limits for the chart are defined in such a manner that the process is considered to be out of control when the time to observe exactly one failure is less than LCL or greater than UCL. Our aim is to monitor the failure process and detect any change of the intensity parameter. When the process is normal, there is a chance for this to happen and it is commonly known as false alarm. The traditional false alarm probability is to set to be 0.27% although any other false alarm probability of false alarm, the control limits can be obtained as (Xie *et al*, 2002):

$$T_U = b^{c^t} = 0.99865$$
$$T_C = b^{c^t} = 0.5$$
$$T_L = b^{c^t} = 0.00135$$

These limits are converted to $m(t_U)$, $m(t_C)$ and $m(t_L)$ form respectively. They are used to find whether the software process is in control or not by placing the points in failure control chart shown in figure 1 & 2. A point below the control limit $m(t_L)$ indicates an alarming signal. A point above the control limit $m(t_U)$ indicates better quality. If the points are falling within the control limits, it indicates the software process is in stable condition. The estimated values of 'a', 'b' and 'c' and their control limits for the transformed data sets are as follows.

Data	No. of samples	Estimated Parameters		
Set		а	В	С
XIE	30	30.526286	0.055202	0.500320
IBM	15	16.419633	0.045773	0.303497

TABLE IV. CONTROL LIMITS OF TIME DOMAIN DATA.

Data Set	No. of samples	Control Limits		
		UCL	CL	LCL
XIE	30	30.485076	15.263143	0.041210
IBM	15	16.397466	8.209817	0.022167

TABLE V. SUCCESSIVE DIFFERENCES OF MEAN VALUES, XIE.

Failure number	Cumulative Time between errors(days)	m(t)	successive differences
1	0.3002	19.756979	0.408055
2	0.3146	19.348924	5.378005
3	0.5393	13.970919	0.272678
4	0.5529	13.698241	0.664307
5	0.5872	13.033934	2.269495
6	0.7192	10.764439	0.774197
7	0.7707	9.990242	0.539432
8	0.809	9.450809	2.479896
9	1.019	6.970914	1.194567
10	1.1487	5.776347	0.039213
11	1.1534	5.737134	0.495318

12	1.2157	5.241816	0.251314
13	1.2496	4.990503	0.617259
14	1.3407	4.373243	0.136012
15	1.3625	4.237231	0.853994
16	1.5178	3.383237	1.052763
17	1.775	2.330474	0.092354
18	1.8029	2.238120	0.061421
19	1.8221	2.176699	0.126466
20	1.8634	2.050232	1.311908
21	2.5681	0.738324	0.161818
22	2.7388	0.576507	0.032392
23	2.7787	0.544114	0.501699
24	4.5393	0.042415	0.029316
25	5.35	0.013099	0.000424
26	5.3727	0.012675	0.002569
27	5.529	0.010106	0.008351
28	6.7368	0.001755	0.000632
29	7.0449	0.001123	0.000439
30	7.3868	0.000684	



Fig. 1. Failure control chart for Xie data

Failure number	cumulative failure time	m(t)	successive differences
1	0.1	14.952484	1.208006
2	0.19	13.744478	1.574687
3	0.32	12.169791	1.190659
4	0.43	10.979132	1.438155
5	0.58	9.540977	1.013654
6	0.7	8.527323	1.322181
7	0.88	7.205142	0.943801
8	1.03	6.261341	1.165251
9	1.25	5.096091	1.063242
10	1.5	4.032848	0.657048
11	1.69	3.375800	0.826468
12	1.99	2.549332	0.659836

TABLE VI. SUCCESSIVE DIFFERENCES OF MEAN VALUES, IBM.

13	2.31	1.889496	0.394222
14	2.56	1.495274	0.466973
15	2.96	1.028301	



Fig. 2. Failure control chart for IBM data

VII. CONCLUSION

In this paper, a theoretical review of the Gompertz SRM is provided; several mathematical formulas of the model's characteristics are obtained. The MLE method is used to estimate the parameters of SRM. This procedure is applied on different sets of failure data collected from literature. For the Xie software failure data the first failure is observed at the 10th instance of time and for the IBM data the successive differences of mean values are within the control limits. Having the successive differences within the limits indicate the failure free operation of the software under consideration. From the obtained results, we can conclude that the proposed method of using SPC techniques for assessing the quality of the software is applicable in several instances.

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